	Type	#	Type L # Hits	Search Text	DBs	Time Stamp
Н	BRS L1	17	7575	(determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near4 (reflectivit\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/10/2 8 08:04
2	2 BRS	1.2	20081	(determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near6 (disc or disk or medium)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/2 8 08:04
m	3 BRS	ГЗ	23627	((laser or light or beam) near5 (chang\$5 or 23627alter\$5 or modif\$6)) near5 (characteristic or behavior or material or shape)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/2 8 08:09
4	BRS L4	1.4	122	122 1 and 2 and 3 and @ad<=19990320	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/10/2
2	BRS	1.6	90259	(first near2 (laser or light or led or beam)) 90259and (second near2 (laser or light or led or beam)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/2 8 08:11
l vo	BRS	17	54	6 BRS L7 54 4 and 6	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/10/2

	Type	Hits	Search Text	DBs
-	BRS	101088	(determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near8 (disc or disk)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
~	BRS	116822	(first near3 (laser or light or beam)) and (second near3 (laser or light or beam))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
m	BRS	7440	((laser or light or beam) near5 (chang\$5 or alter\$5 or modif\$6 or correct\$5)) with (reflect\$5 near6 surface)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
4	BRS	290	((determin\$5 or detect\$5 or measur\$5 or linspect\$5 or examin\$5 near8 (disc or disk) and ((first near3 (laser or light or beam)) and (second near3 (laser or light or beam)) and ((laser or light or beam)) or al ((laser or light or beam) near5 (chang\$5 or alter\$5 or modi\$6 or correct\$5)) with (reflect\$5 near6 surface)) and @dd<=19990320	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
LS.	BRS	178581	optic\$3 near3 (storage or disc or disk)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM IDB
9	BRS	234	(((determin\$5 or detect\$5 or measur\$5 or Inspect\$5 or examin\$5) near8 (disc or disk) and (first near3 (laser or light or beam)) and (second near3 (laser or light or beam)) and ((laser or light or beam) near5 (chang\$5 or alter\$5 or modif\$6 or correct\$5) with (reflect\$5 near6 surface) and (add=1990020) and (optic\$3 near3 (storage or disc or disk))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
7	BRS	46065	(determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near9 (surface near7 reflect\$6)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
ω	BRS	183	((determin\$5 or detect\$5 or measur\$5 or Inspect\$5 or examin\$5 near (disc or disk) and (first near3 (laser or light or beam)) and (second near3 (laser or light or beam)) and (second near3 (laser or light or beam)) or alter\$5 or modi\$6 or correct\$5) with (reflect\$5 near6 surface) and @ad<=19990320) and (Idetermin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near9 (surface near7 reflect\$6))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB

	Type	Hits	Search Text	DBs
0	BRS	1591	determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near6 (surface near4 reflectivity)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
10	10 BRS	16	((((determins) or detects) or measurs5 or measurs5 or ann speces or examins5) near (disc or disk) and (cfirst near3 (laser or light or beam)) and (second near3 (laser or light or beam)) and ((laser or light or beam)) and ((laser or light or beam)) and ((dlaser or light or beam)) and (determins5 or modifs6 or correct55) with creflect55 near6 eurface)) and (determins5 or measurs5 or inspect55 or examins5) near9 (surface near7 measurs5 or inspect55 or examins5 or detect55 or measurs5 or inspect55 or examins5) near9 (surface near7 (surface near4 reflectivity))	USPAT, US-PGFUB, EPO; JPO; DERWENT; IBM_TDB
11	11 BRS	5529	(laser or light or beam) near9 ((chang\$5 or alter\$5 or modif\$6) near7 ((reflect\$5 or characteristic\$2 or behavior) near4 surface))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
12	12 BRS	£ 4.	((first near3 (laser or light or beam)) and (second near3 (laser or light or beam)) and (laser or light or beam)) and (laser or light or beam) near9 ((chang\$5 or alter\$5 or modif\$6) near7 ((reflect\$5 or characteristic\$2 or behavior) near4 surface)) JPO; DERWENT; IBM_TDB and ((determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near6 (surface near4 reflectivity)) and @ad<=19990320	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_IDB

	Type	1	Type L # Hits	Search Text	DBs
-	BRS	17	13573	(light or laser or led) with ((perturb\$5 or disturb\$5 13573 or modif\$7 or chang\$5 or alter\$5) near5 (die or area or region))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
2	BRS	17	5505	5505 (determin\$5 or detect\$5 or analyz\$5 or inspect\$5 or examin\$5) near5 (reflectivit\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB
m	BRS	E3	163	1 and 2 and @ad<=19990320	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB
4	BRS	1.4	803	(determin\$5 or detect\$5 or analyz\$5 or inspect\$5 or examin\$5) near5 (reflectivit\$3 near3 surface)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB
5	BRS	1.5	21	1 and 4 and @ad<=19990320	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB
٥	BRS	Te Tre	59	((((light or laser or led) near3 (source or beam or diode)) with ((perturb\$5 or disturb\$5 or modif\$7) or chang\$6 or alter\$5) near5 (die or area or region))) and ((determin\$5 or detect\$5 or area or region))) inspect\$5) near5 semiconductor) and @ad<=20000419) not (semiconductor adjlaser)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
7	BRS	L7	58	6 not 5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB
8	BRS	L8	10596	(light or laser or led) near5 ((perturb\$5 or 10596disturb\$5 or modif\$7 or chang\$5 or alter\$5) near6 (die or area or region))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
o	BRS	67	6215	6215 1 and 8 and @ad<=19990320	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB
10	10 BRS	L10	L10 112	8 and 2 and @ad<=19990320	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB